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Comparative study of Cu₂ZnSnSe₄ solar cells growth on transparent conductive oxides and molybdenum substrates

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CZTSe/FTO interface.

- 8 ² EDF R&D, 30 Route Départementale 128, 91120, Palaiseau, France
- 10 Abstract

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Cu₂ZnSnSe₄ (CZTSe) thin films have been synthetized by cosputtering followed by a 11 selenization treatment on Mo and transparent conductive oxide (TCO) coated soda lime glass 12 substrates, such as ZnO:Al and SnO₂:F (FTO). The aims of the present work is to investigate 13 the impact of the TCO substrates on the CZTSe growth, the reactions at the back contact and 14 the electrical properties of solar cells. The results show that the morphology of CZTSe is 15 affected by the TCO back contacts. It is found that TCO acts as a diffusion barrier of Na from 16 soda lime glass to CZTSe. Thus low incorporation of Na during the annealing could explain 17 the difference in grain size of CZTSe deposited on TCO. Moreover it is evidenced chemical 18 reactions between TCO and CZTSe which affects the interface. While the efficiency up to 8 19 % is obtained for CZTSe based solar cells deposited on Mo substrate, the efficiency drops to 20 2.3 % for the solar cells deposited on FTO. The low efficiency is explained by the 21 recombination at the back contact due to the formation of a very thin layer of ZnO at the 22

I. Introduction

The polycrystalline kesterite Cu₂ZnSn(S,Se)₄ (CZTSSe) solar cell is a promising thin-film solar cell technology owing to the abundance of its constitutive elements and its low production cost. Solar cells with a conversion efficiency up to 12.7% has been reported [1]. Most of the CZTSSe based solar cells have been fabricated on Mo substrate which has many advantages (good thermal stability, ohmic contact with CZTSSe) [2,3]. However its opaque nature limits its use as a back contact for semi-transparent, bifacial or tandem solar cells. Thus the use of transparent conductive oxides (TCO) as back contact can offer new possibilities for the application of CZTSSe absorber. The most common TCOs used in chalcogenide solar cells are tin doped indium oxide (In₂O₃:Sn or ITO), fluorine doped tin oxide (SnO₂:F or FTO) or aluminium doped zinc oxide (ZnO:Al).

Many groups have investigated the Cu(In,Ga)Se₂ (CIGS) based solar cells deposited on TCO [4-9]. The best efficiencies up to 15.2% are obtained using In₂O₃:Sn (ITO) as back contact [4]. In the case of kesterite based solar cells only very few studies have been reported using this type of back contact. CZTSSe solar cells have been deposited on ITO [10-14] and best efficiencies up to 5.8 % are reached under bifacial illumination [15]. The low efficiency in these solar cells is reported to be due to an interfacial reaction at ITO back contact, which induces the Indium diffusion into the CZTSSe absorber and formation of an oxide SnO_x thin layer, thus degrading the CZTSSe rear interface [12]. CZTSSe based solar cells have also been deposited on FTO [13,16-18], reaching efficiencies up to 7.7% using a Mo nanolayer at the CZTSSe/FTO interface [19]. Lee & al. reported a superstrate CZTSSe based solar cells deposited on ZnO wire and completed with a graphite electrode reaching efficiencies of 1.2 % [20].

In this work, we compared the growth of Cu₂ZnSnSe₄ (CZTSe) deposited on two different glass coated TCOs: AZO (ZnO:Al) and FTO. The results are compared to cells with classical Mo back contact [21,22]. The effect of substrate combined with the deposition temperature of the absorber on morphology, composition, crystallinity of CZTSe and the optoelectronic properties of the solar cells will be discussed.

II. Experimental section

- Thin Cu-Zn-Sn precursors were deposited on Mo, SnO₂:F (3% of F) (FTO) and ZnO:Al (3%
- of Al) (AZO) coated soda lime glass substrates using RF magnetron co-sputtering from Cu,
- Zn and Sn targets at room temperature with [Cu] / ([Sn]+[Zn]) and [Zn] / [Sn] values
- respectively close to 0.7 and 1.2 (Cu-poor, Zn-rich). These films were then annealed inside a
- graphite box under a pure selenium atmosphere (Se) provided by an amount of 60 mg of Se
- 61 pellets. The annealing was done at 600 °C for 15 min [21]. For optoelectronic characterization
- of the cells, after annealing, a layer of 50 nm of CdS was deposited on the CZTSe absorber by
- chemical bath deposition and a double layer of ZnO:i / AZO of around 350 nm was deposited
- by sputtering to complete the solar cell. Before the deposition of the CdS layer, surface
- etching has been underwent on the CZTSe absorber with KCN, KMnO₄+H₂SO₄+Na₂S and
- 66 $(NH_4)_2S$ [23].
- The AZO as back contact was grown on a 3-mm-thick soda-lime glass following the same
- 68 procedure than the AZO used for the front contact. The layer was deposited by radio-
- 69 frequency (RF) sputtering using an AZO ceramic target under argon plasma and O₂ flux and
- at a RF power density of 3W/cm². Two thicknesses of AZO (500 nm and 1300 nm) were
- 71 compared.
- 72 The FTO substrate is a commercially available product from Solems. The FTO layer was
- deposited by spay pyrolysis on a 2-mm-thick soda-lime glass. Its thickness is 600-700 nm
- with a roughness of ± 40 nm. The sheet resistance of the samples was measured by 4-point
- 75 probe.
- As the CZTSe is annealed at high temperature (500 to 550°C) under Se atmosphere and in
- order to evaluated the evolution of the TCO parameters under similar conditions, the AZO
- and FTO layers were also annealed separately. The substrates were placed with 50 mg of Se
- 79 pellets in the graphite box inserted in a tubular furnace under atmospheric pressure of Ar. A
- 80 lower amount of Se has been used as ZnO layer is directly in contact with the Se atmosphere.
- 81 The box was heated at 500°C or 600°C with a linear heating ramp of 15 min, and the
- 82 temperature was maintained for 45 min.
- The composition of the absorber has been studied by Glow discharge optical spectroscopy
- 84 (GD-OES) measurements. The calibrated signals with a reference give quantitative
- information of the presence of the elements in the samples. The crystallinity of the absorbers
- was examined by X-ray diffraction (XRD) with a Panalytical Empyrean X-ray diffractometer
- using CuK_{α} radiation (1.5419Å) in the classical Bragg-Brentano and grazing incidence X-ray

diffraction (GIXRD) setups. An incidence angle of 0.5° has been used in order to probes the whole thickness of layers with XRD and to obtain an optimal signal. Raman microprobe measurements were conducted using a HR800-UV Horiba Jobin Yvon spectrometer with 532 nm- and 385 nm lasers and a X50 objective.

In order to characterize the interface between the TCO and the CZTSe absorber, the sample was encapsulated using a transparent epoxy and a 3-mm borosilicate glass and then a lift-off was performed allowing the mechanical separation of the CZTSe layer from the glass/back contact [2,3].

The surface morphology of the samples were investigated by a scanning electron microscopy (SEM) using a Leo Supra 35 field emission gun (FEG) with 15 kV voltage. The electrical properties of the solar cells were characterized by current voltage measurements in dark and light illumination at 25°C (AM1.5 global spectrum). Quantum efficiencies were collected using Oriel IQE-200 TM instruments.

III. Results and discussions

The chemical, electrical and optical properties of ZnO:Al (AZO) and SnO₂:F (FTO) layers can change during the CZTSe process at high temperature (600 °C) under Se atmosphere. In order to evaluated the evolution of the TCO parameters under similar conditions, The Glass/600-nm-thick AZO, Glass/1300-nm-thick AZO and the Glass/650-nm-thick FTO substrates were placed with 50 mg of Se pellets in graphite box under atmospheric pressure of Ar. The evolution of the square resistance of samples before and after annealing at 500°C and 600°C are presented on Fig.1. The FTO layer seems to be perfectly stable at high temperature as the square resistance remains constant at about 6 Ω / \square whatever the annealing temperature. For the annealing of the 500-nm-thick AZO, both 500 and 600°C under Se atmosphere lead to a dramatically increase of the sheet resistance while annealing of the 1300-nm-thick AZO only moderately increases. Indeed, under the same annealing conditions at 600°C, the sheet resistance is considerably lower for a 1300 nm-thick AZO layer (16 Ω / \square) than the 500 nm-thick AZO layer (200 Ω / \square). This means that the AZO degradation seems to be a surface effect explaining the lower sheet resistance of the 1300-nm-thick AZO layer.

In order to confirm this hypothesis the crystallinity and the morphology of glass/1300-nm-thick and the Glass/650-nm-thick FTO were analyzed by XRD and SEM measurements

- before and after annealing. SEM cross sectional images of FTO and AZO (1300nm)
- substrates before and after Se annealing are shown in Fig.2. While no change is observed for
- 121 FTO based samples before and after annealing (Fig.2a and 2b), Fig.2c and 2d reveal
- morphological changes of AZO induced by the Se annealing. The columnar structure of the
- AZO layer disappears after annealing under Se and a bilayer of 1000 nm and 500 nm is
- observed. Moreover, the formation of holes is observed at the interface of the two layers.
- Differences in lattice parameter between the hexagonal crystal structure of ZnO and the cubic
- structure of ZnSe, may cause the formation of cavities at the interface between the ZnSe and
- 127 ZnO layers.
- Grazing incidence X-ray diffraction (GIXRD) measurements were performed on FTO and
- AZO coated substrates before and after annealing at 600°C under Se atmosphere. Fig.3
- confirms that FTO is quite stable under Se atmosphere, as the XRD diagrams are exactly the
- same before and after annealing.
- 132 It is also observed that the (103)/(002) ratio of ZnO increases from 1.3 before annealing to 2.6
- after annealing. In parallel the (103)/(102) ratio of ZnO increases from 6.7 before annealing to
- 7.6 after annealing. Based on these results it appears that there is change on the preferential
- orientation of ZnO after annealing.
- Moreover several new peaks in addition to ZnO peaks are observed after annealing which are
- assigned to ZnSe phase (PDF # 00-037-1463) confirming the formation of a thin ZnSe layer at
- the surface of the film as observed on SEM pictures (Fig.2d). The formation of ZnSe could
- 139 result from substitution of oxygen with selenium. Reaction of oxides phases with
- chalcogenide phases through substitution of oxygen by the chalcogen (S, Se) have already
- been studied in previous works [24,25].
- During the annealing, the transparent conducting back contact is not only in contact with Se
- but also with the CZTSe phase and in consequently with its associated binaries. The reactivity
- of the binaries with the TCO back contact can be estimated by the calculation of the standard
- Gibbs free energy of the reaction (ΔG_f). Table 1 summarizes the ΔG_f of different reactions
- potentially occurring at the interface between the TCO and the CZTSe absorber [26]. If ΔG_f <
- 0, the reaction is thermodynamically favored. The CZTSe decomposition is not possible if any
- reaction with the constituent binaries (Cu₂Se, Sn₂Se₃, ZnSe) is thermodynamically not
- 149 allowed.

For the AZO back-contact, the calculated ΔG_f for the reaction between ZnO and Se is negative. Therefore, ZnSe layer can be formed at the interface between the CZTSe and the AZO. The reaction of ZnO with the Se vapors leads to the emission of SeO₂ gas.

On the opposite, for the FTO back-contact, the calculated ΔG_f calculated for the reactions between SnO₂ and Se, and Cu₂Se are positive. Thus FTO would not react during the CZTSe formation. The CZTSe process is likely to impact the AZO layer performance leading not only to a reduction of the doping concentration but also to some thermodynamically favored reactions between CZTSe and AZO. On the opposite, the FTO layer is perfectly stable up to 600° C. However, it is important to note that the kinetic of the reaction may be too long and that the annealing process is not at thermodynamically equilibrium. Therefore, the experimental results can differ from the conclusions based on these calculations.

SEM analysis of CZTSe absorber deposited on Mo, AZO, and FTO are shown in Fig.4. The films are dense whatever the substrate. However, the morphology of grains depends to the back contact. Indeed, while larger grains of CZTSe > 2μm are formed on Mo substrate (Fig.4a), smallest grains (< 1 μm) are formed on FTO and AZO substrates (Fig.4b and 4c, respectively). More particularly, in the case of AZO coated substrate, voids are observed at the interface between CZTSe and AZO. The voids could be attributed to the reaction between Se and ZnO during the annealing to form the thin ZnSe layer and the emission of SeO₂ gas in agreement with the Fig.2. Thus SeO₂ diffusion into the CZTSe layer could degrades the interface.

The distribution of the chemical elements through the absorber layers deposited on Mo, FTO and AZO, obtained by GD-OES, are shown in Fig.5. For Mo and FTO coated substrates (Fig.5a and 5b, respectively), the profiles of Cu, Zn, Sn and Se are homogeneous throughout the thickness in agreement with the literature [13]. As observed in SEM pictures (Fig. 4d) the interface between CZTSe and FTO is rough. The interface roughness broadens the observed elemental profiles in GDOES. Moreover, as the Sn is both in the coating and in the substrate layer, it is not obvious to get a sharp interface between CZTSe and FTO and a gradual increase of Sn and O at the back side is observed while Cu, Zn and Se decreases. As shown by the thermodynamic calculations, FTO is quite stable at these temperatures confirming that the gradual increase of Sn and O at the CZTSe/FTO is not caused by the diffusion of Sn from FTO into CZTSe.

- For the AZO coated substrate (Fig. 5c), the profiles of Cu and Sn appear relatively
- homogenous. However, the profiles of Zn and Se strongly vary through the thickness. Indeed,
- a segregation of Zn is visible at the back side. It seems that the composition of the substrate
- considerably modify the growth of CZTSe and especially its Zn content.
- To highlight the impact of the AZO and FTO on the Na diffusion, the Na concentration in the
- 186 CZTSe layer was also estimated by GD-OES. The standard Mo substrate allows the Na
- diffusion from the soda-lime glass to the CZTSe through the Mo layer. However the Na
- intensity for CZTSe on FTO and AZO back-contact are closed to 0, meaning that both FTO
- and AZO back-contacts hinder the diffusion of Na. The low diffusion of Na through TCO, in
- particular AZO and FTO has been evidenced on CIGSe based solar cells [8,27-29].
- 191 XRD patterns of CZTSe absorbers deposited on Mo, FTO and AZO are shown in Fig.6. The
- signature of Mo, FTO and AZO layers are visible. Moreover, the main reflections (112) at
- 193 27.29°, (220) at 45.28°, and (312) at 53.64° of the CZTSe phase are clearly observed
- whatever the substrate [21]. For the Mo coated substrate, the SnSe₂ secondary phase (PDF
- 195 089-3197) are also visible (Fig.6a) [30]. The (112) orientation of CZTSe is shown on a short
- range in the inset part of Fig.6. FWHM of (112) peak is sharper for CZTSe deposited on Mo
- and FTO than the one on AZO indicating a higher crystalline quality of CZTSe phase. These
- results are in agreement with the previous results in Fig.4 and 5 which show the disrupted
- 199 growth of CZTSe deposited on AZO.
- Due to the similar crystal structures of the ZnSe and Cu₂SnSe₃ with CZTSe phases, it is not
- 201 possible to conclude on the basis of X-ray measurements whether CZTSe if clearly formed.
- Thus, Raman spectroscopy is used to identify it. Raman spectra obtained with a 532 nm-laser
- 203 wavelength of CZTSe films deposited on the different substrates Mo, FTO and AZO are
- shown in Fig.7a. Raman spectroscopy confirms the formation of the CZTSe phase on the
- 205 different coated substrates.
- It is important to note that even if SEM and XRD analysis have identified a thick ZnSe layer
- at the surface of AZO (Fig.2b, Fig. 3) after annealing, no ZnSe signal is observed for the
- 208 CZTSe/AZO stack. In fact, the penetration depth of Raman spectroscopy is some hundreds of
- 209 nanometers. Thus Raman spectroscopy cannot detect the signal of ZnSe at the interface
- between CZTSe and AZO.
- 211 Moreover, an additional peak attributed to the SnSe₂ phase is visible on the surface of CZTSe
- 212 film deposited on FTO while it has not been detected by XRD. SnSe₂ is not a continuous film
- and could escape from the Raman and XRD analysis [30]. These complementary results show

- 214 that the SnSe₂ phase appears whatever the substrate and only depends on the growth
- 215 conditions of CZTSe.
- In order to access the interface between CZTSe and the TCO layer, lift-off technique has been
- used. However lift-off has been unsuccessful for CZTSe deposited on AZO. Fig.7b shows the
- 218 Raman spectra of FTO coated substrate using UV laser wavelength after lift-off of CZTSe.
- 219 FTO coated substrate before the CZTSe deposition is shown as reference. The FTO phase is
- observed and corresponds to the peak centered at 636 cm⁻¹ [31]. FTO coated substrate after
- lift-off reveals the presence of a secondary phase with 2 peaks at 568 cm⁻¹ and 1142 cm⁻¹. This
- secondary phase fully absorbs UV laser wavelength and the peak of FTO centered at 636 cm⁻¹
- is no longer visible. These 2 peaks are attributed to the 1st and 2nd order vibrations of the
- 224 ZnO phase [32].
- 225 As Zn can be only provided by CZTSe layer, the ZnO phase at the interface between CZTSe
- and FTO could indicate the decomposition of CZTSe which provides the Cu, Zn and Sn
- 227 elements. Thus the reaction of these elements with oxygen coming from FTO could product
- binary oxides. However, no additional secondary phases, such as Cu_xO has been observed.
- The formation of oxide secondary phases at the interface between chalcogenide and TCO has
- been observed in previous works. For example, for CIGSe films deposited on ITO, the
- presence of a Ga₂O₃ resistive layer is reported [4,7] forming an electrical barrier for carrier
- transport [27,28]. For CZTSe films deposited on ITO, the formation of SnO₂ phases is
- reported. However, the effect of SnO₂ on the electrical properties of solar cells has been found
- 234 negligible [12,18].
- In order to assess the impact of the back contact on the electrical properties of solar cells IV
- 236 measurements are performed on completed cells. Unfortunately all solar cells were shunted in
- the case of AZO/CZTSe based solar cells. In Fig.8.a, I-V curves for the best solar cells
- deposited on Mo/glass and FTO/glass substrates are reported. Their electrical parameters are
- summarized in Table 2. It can be found that all the electrical parameters of the solar cells
- deposited on FTO are lower than the ones deposited on Mo. For CZTSe absorbers deposited
- on Mo, the best solar cells have led to efficiencies up to 8.0 % [21,22]. The best efficiency of
- solar cells on FTO back contact is about 2.3%. The solar cells deposited on FTO suffer from a
- low FF, J_{sc} and V_{oc}. In fact, I-V characteristics under illumination of the solar cells deposited
- on FTO exhibits a slight slope at 0 V which shows that the solar cell has a current collection
- 245 that depends on the voltage. The slope is higher under illumination than in the dark indicating
- the presence of recombination. It is well known that absence of Na is detrimental for the
- 247 CZTSe cell (low doping concentration or high defect density), and the Na has to be supplied

by an external source. Moreover the back contact/CZTSe interface is the p-contact of the cell and has to be ohmic [19]. It has been shown that when the CZTSe is grown directly on FTO, an ohmic contact is achieved. However, the series resistances of the cells are slightly higher than the reference cells on Mo substrate. In our case a rectifying behavior is observed either due to the formation of a pn-junction between the n-type TCO and the p-type CZTSe or due to the high contact resistance of the ZnO secondary phase at the CZTS/SnO₂ interface. In fact ZnO is generally n-doped and therefore degrades the performance of the cell.

Fig.8b shows the EQE of the best solar cells deposited on Mo and FTO. The EQE spectrum exhibits a maximum around 560 nm at a level about 80% whatever the substrate. However, EQE drastically decreases with the wavelengths from 600 nm to 1200 nm for FTO coated substrate in contrary to Mo coated substrate. Integrated Jsc from EQE, obtained for the both solar cells, are 32.02 mA/cm² and 21.5 mA/cm² for CZTSe/Mo and CZTSe/FTO, respectively. These values are slightly higher than the ones obtained by I-V analysis. Low EQE is correlated with a low collection efficiency of the absorber, such as the losses at highest wavelengths in the near IR region could also be due to a recombination rate raised to the back contact [33,34]. Thus, several reasons can be reported to understand the low efficiency of CZTSe solar cell on FTO. On the one hand, in the case of Mo back contact, the formation of MoSe₂ at the CZTSe / Mo interface forms an ohmic contact. Thus, low recombination rate contributes to increase Voc, Jsc and FF. In the case of FTO back contact, high recombination rate comes from defects at the contact between CZTSe and FTO. In fact, ZnO secondary phases or diffusion of the oxygen to CZTSe could damage the interface. On the other hand, it has been observed that the TCO prevents the diffusion of Na through CZTSe. The diffusion of Na through CZTSe has a beneficial effect on doping concentration and defect density of the absorber. Thus, the improvement of the interface quality between CZTSe and FTO could also increase Voc and FF [28, 35-37].

IV. Conclusion

CZTSe based solar cells deposited on Mo, ZnO:Al (AZO), and SnO₂:F (FTO) coated substrate have been studied. It has been found that the annealing temperature under Se has no impact on the FTO substrate up to 600°C, whereas the temperature should remain below 500°C for the 1300-nm-thick AZO. During the CZTSe deposition, FTO substrate is the most stable: no reaction are thermodynamically favored between the CZTSe phases and FTO.

However, CZTSe decomposition reaction is thermodynamically possible at the ZnO interface with the formation of a ZnSe phase. Moreover both FTO and AZO layer hinder the Na diffusion from the glass to the CZTSe absorbers leading to a lack of Na compared to the standard Mo substrate. Thus Solar cells based on CZTSe were made with an efficiency of 2.3% on FTO while solar cells CZTSe deposited on Mo up to 8.0 %. Low efficiency of CZTSe solar cell on FTO coated substrate suffers of recombination at the back contact which limits Voc, Jsc and FF. Low efficiency has been explained by the presence of the ZnO secondary phase at the back contact and the low diffusion of Na through CZTSe.

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395 Table

396

Table 1 Gibbs free energy of the potential reactions at the CZTS/back-contact.

	Gibbs free energy at 500°C			
Reaction equation	Reaction equation per mol of			
	Mo, ZnO or SnO_2 $\triangle Gf$			
	(kJ/mol)			
$Mo+Se_2 = MoSe_2$	-153			
$2ZnO+1.5Se_2(g) = 2 ZnSe + SeO_2(g)$	-30			
$Cu_2Se + ZnO = Cu_2O + ZnSe$	87			
CuSe + ZnO = CuO + ZnSe	63			
$SnO_2 + 1.5Se_2(g) = SnSe_2 + SeO_2(g)$	176			
$SnO_2 + Se_2(g) = SnSe(g) + SeO_2(g)$	286			
$2Cu_2Se + SnO_2 = 2Cu_2O + SnSe_2$	287			
$2CuSe + SnO_2 = 2CuO + SnSe_2$	241			

398

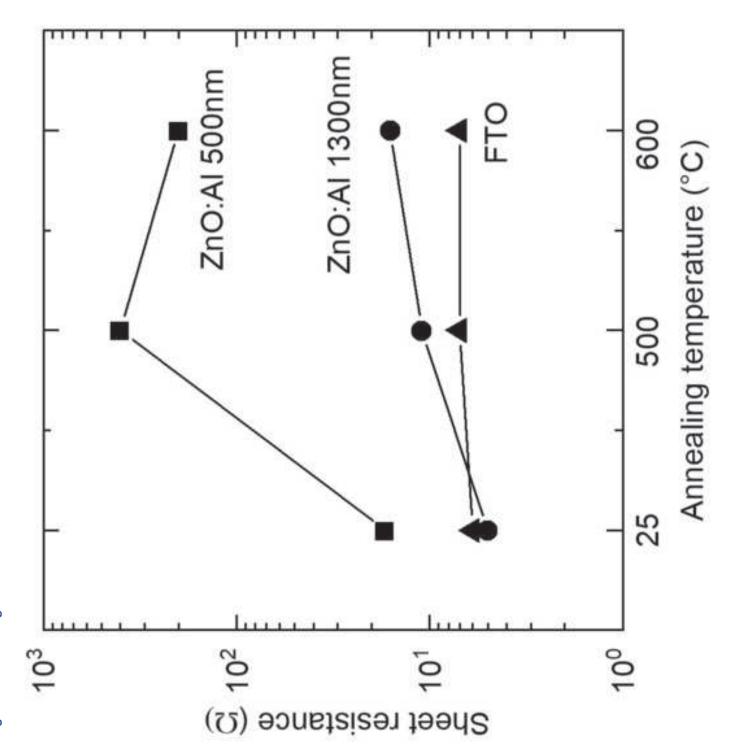
Table 2 Electrical parameters of CZTSe based solar cells deposited on Mo/glass and FTO/glass

	Voc	Jsc	FF (%)	Eff (%)	Eg (eV)
	(mV)	(mA/cm^2)			
CZTSe/Mo	460	28.6	61	8.0	1.03
CZTSe/FTO	290	18.6	43	2.3	1.07

401

403	Figures
404	
405 406	Figure 1 Sheet resistances of AZO(500 nm), AZO(1300 nm), and FTO before and after annealing at different temperature under Se atmosphere for 45 min
407	
408 409	Figure 2 SEM morphologies of as deposited a) AZO, b) FTO and annealed c) AZO, d) FTO at 600°C for 45 min under Se atmosphere
410	
411 412	Figure 3 GIXRD patterns of a) FTO and b) AZO before and after annealing at 600°C under Se atmosphere for 45 min
413	
414 415	Figure 4 SEM morphologies of CZTSe absorber deposited on a), b) Mo, c),d) FTO et e),f) AZO
416	
417	Figure 5 GD-OES composition profiles for CZTSe deposited on a) Mo, b) FTO and c) AZO
418	
419	Figure 6 XRD patterns of CZTSe films deposited on Mo, AZO and FTO
420	
421	Figure 7 Raman spectra of a) CZTSe deposited on different substrates Mo, FTO and AZO at
422 423	532 nm and b) FTO substrate at 325 nm laser wavelength before CZTSe deposition and after lifted off CZTSe
424	
425	Figure 8 J(V) curves of CZTSe based solar cells deposited on Mo/glass and FTO/glass

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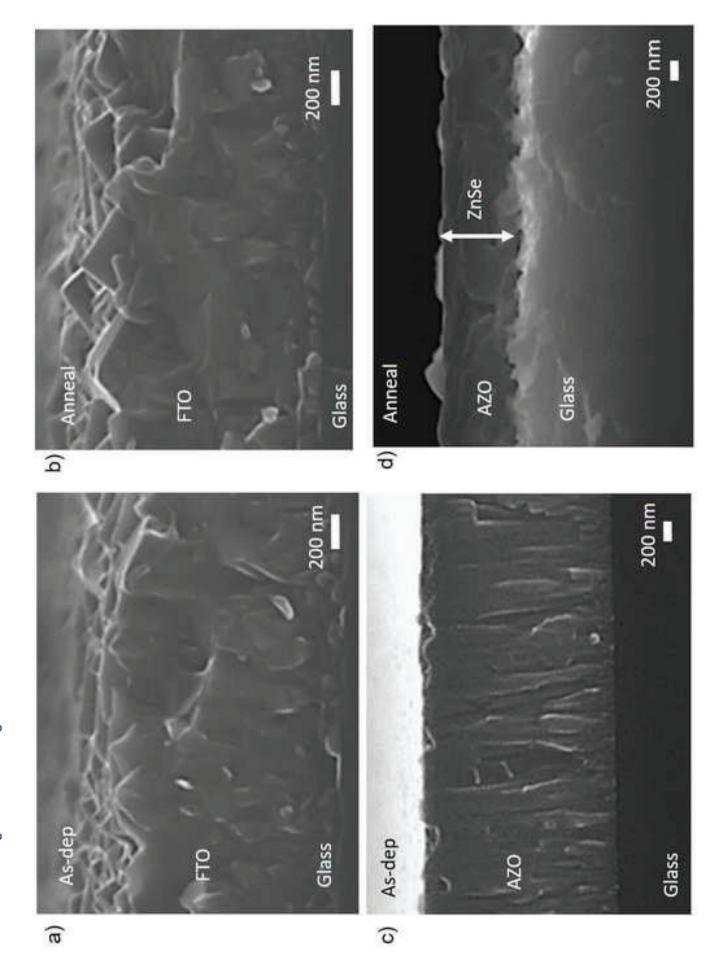


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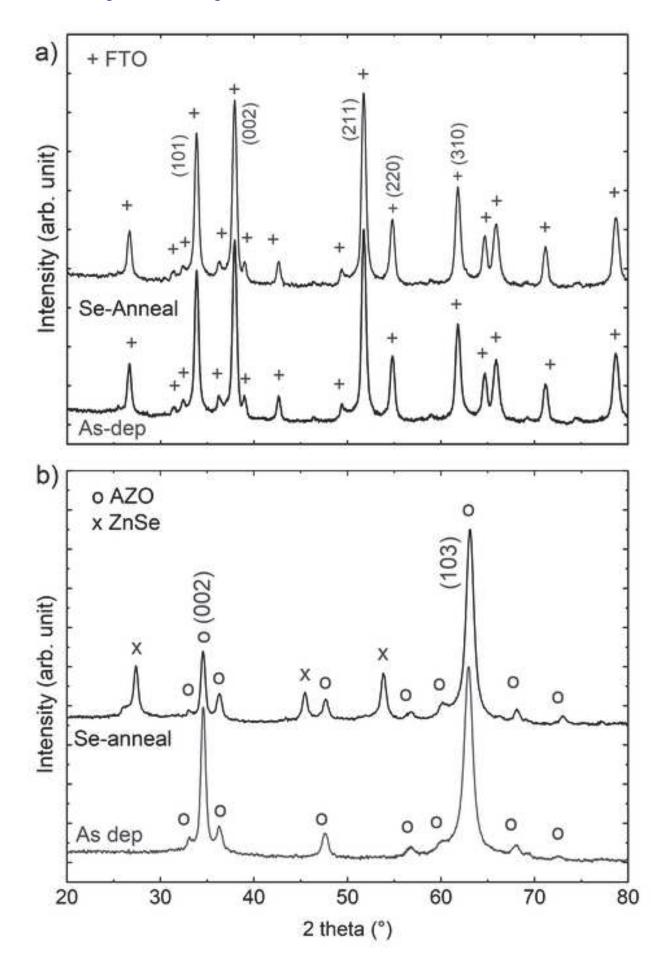


Figure 4
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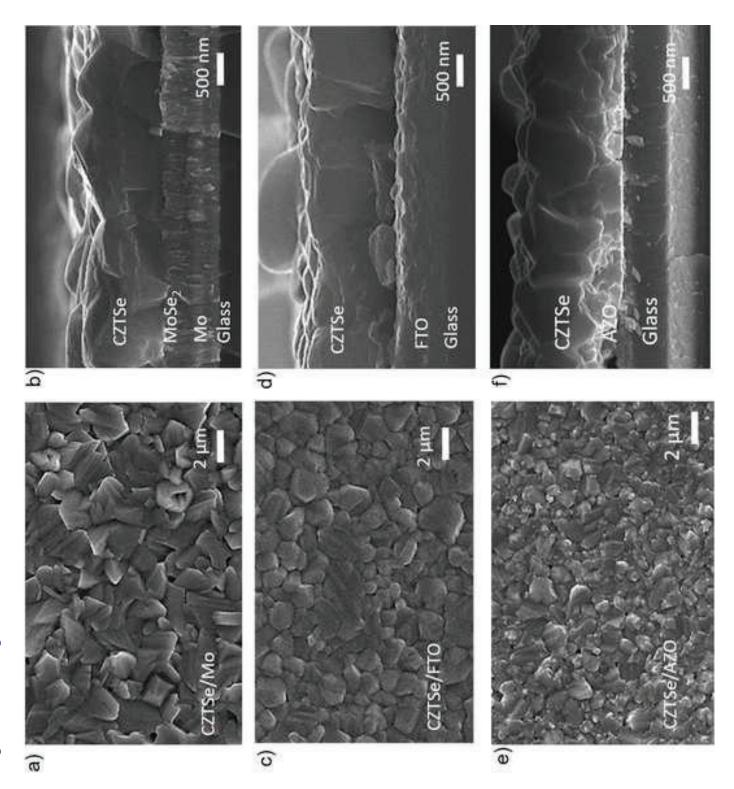


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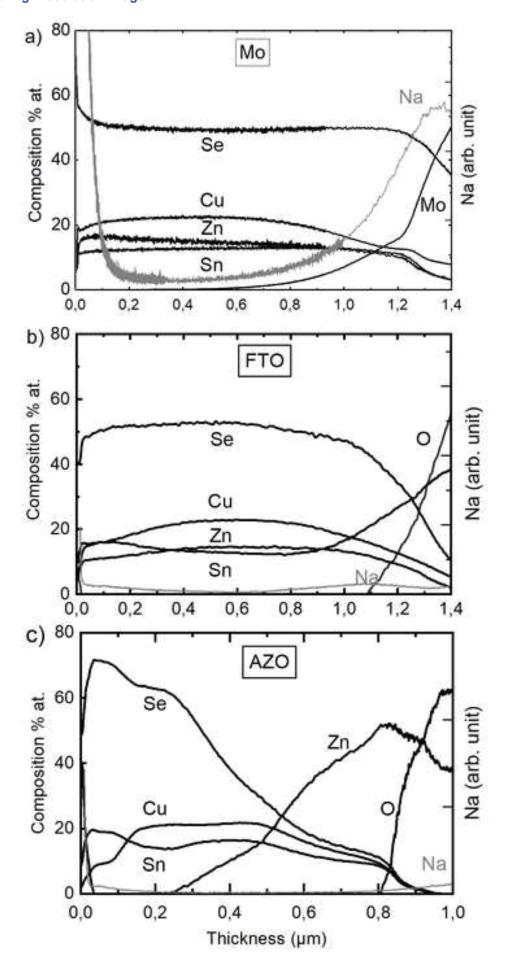


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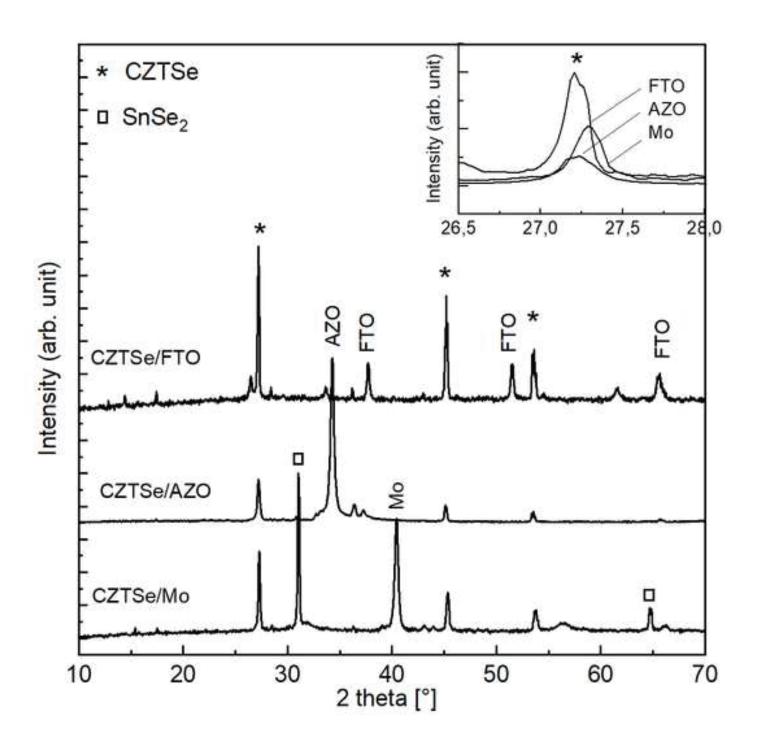


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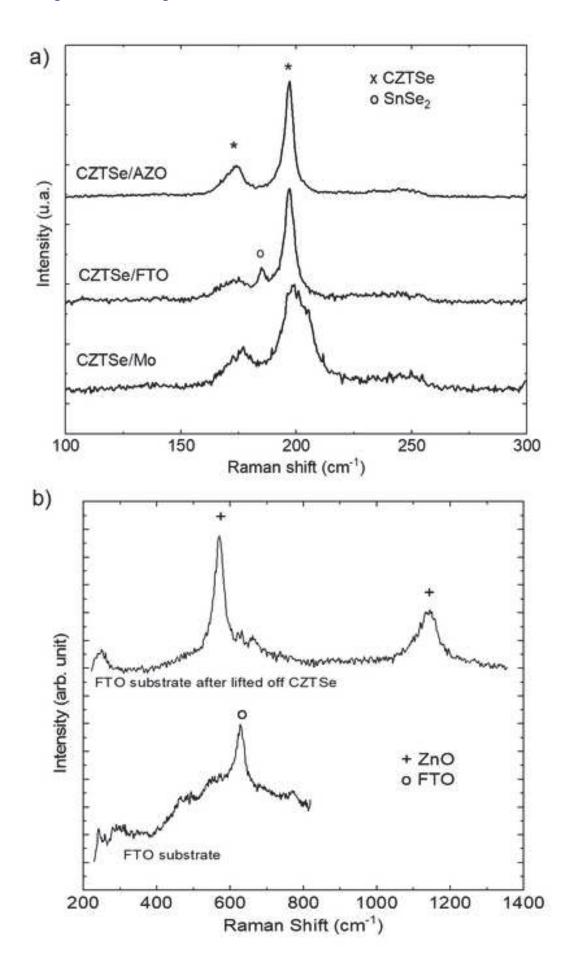


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